54S/74S89 54LS/74LS89 (Preliminary data)

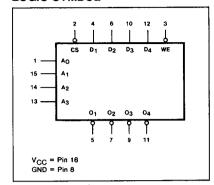
DESCRIPTION

The "89" is a 64-Bit high-speed Read/Write Random Access Memory for use as a "scratch pad" memory with non-destructive read-out. Memory cells are organized in a matrix to provide 16 words of four bits each. Four buffered Address (A₀-A₃) inputs are decoded on the chip to select one of the sixteen memory words for read or write operations. Four buffered Data inputs (D₁-D₄) and four open-collector data outputs are provided for versatile memory expansion. Data at the outputs is inverted from the data which was written into the memory. When the write mode is selected the outputs are the complement of the data inputs.

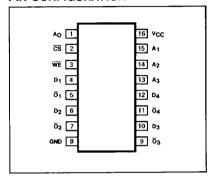
FEATURES

- 16-words by 4-bit memory
- · On-chip address decoding
- . Inverted data at outputs
- Open collector outputs for easy expansion

LOGIC SYMBOL



PIN CONFIGURATION



ORDERING CODE (See Section 9 for further Package and Ordering Information)

PACKAGES			RANGES CC to +70°C	MILITARY RANGES V _{CC} =5V ± 10%; T _A =-55°C to +125°C				
Plastic DIP	N74S89N	•	N74LS89N					
Ceramic DIP	N74S89F	•	N74LS89F	S54S89F	•	S54LS89F		
Flatpak								

INPUT AND OUTPUT LOADING AND FAN-OUT TABLE(a)

PINS	DESCRIPTION		54/74	548/748	54LS/74LS
A ₀ -A ₃	Address inputs	l _{įΗ} (μΑ) l _{IL} (μΑ)		25/10(a) -150/-100(a)	20 -100
CS	Chip Select (active LOW) enable input	i _{IH} (μΑ) i _{IL} (μΑ)		25/10(a) -150/-100(a)	20 -400
WE	Write Enable (active LOW) input	I _{IH} (μΑ) I _{IL} (μΑ)		25/10(a) -150/-100(a)	20 -400
D ₁ - D ₄	Data inputs	Ι _{ΙΗ} (μΑ) Ι _{ΙL} (μΑ)		25 / 10(a) -150 / -100(a)	20 -400
Ō ₁ -Ō ₄	Data (inverting) outputs	I _{OH} (μΑ) I _{OL} (mA)		+100 16	+100 12/24(a)

NOTE

a. The slashed numbers indicate different parametric values for Military/Commercial temperature ranges respectively.

FUNCTIONAL DESCRIPTION

The "89" is a high-speed array of 64 memory cells organized as 16 words of four bits each. A one-of-sixteen address decoder selects a single word which is specified by the four Address inputs (A₀-A₃). A READ operation is initiated after the address lines are stable when the Write Enable (WE) input is HIGH and the Chip Select-Memory Enable (CS) input is LOW. Data is read at the outputs inverted from the data which was written into the memory.

A WRITE operation requires that the \overline{WE} and \overline{CS} inputs be LOW. The address inputs must be stable during the WRITE mode for predictable operation. When the write mode is selected the outputs are the complement of the data inputs. The selected memory cells are transparent to changes in the data during the WRITE mode. Therefore, data must be stable one setup time before the LOW-to-HIGH transition of \overline{CE} or \overline{WE} .

MODE SELECT—FUNCTION TABLE

OPERATING	IN	NPUT	OUTPUTS		
MODE	ĊŚ	WE	Dn	Ōn	
Write	L L	L L	L H	H	
Read	L	н	х	Data	
Inhibit Writing	Н	L L	Н	H	
Store-Disable Outputs	Н	Н	X	Н	

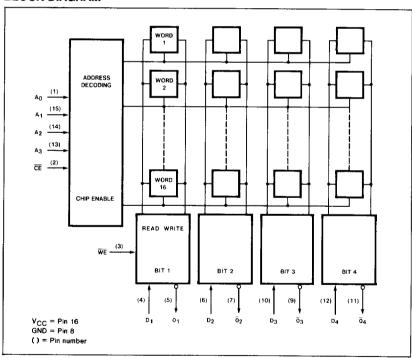
H = HIGH voltage level

L = LOW voltage level

X = Don't care

Data = Read complement of data from addressed word location

BLOCK DIAGRAM



DC CHARACTERISTICS OVER OPERATING TEMPERATURE RANGE(b)

PARAMETER			TEST CONDITIONS		54/74		548/748		54LS/74LS		
		TEST CON			Min	Max	Min	Max	Min	Max	UNIT
.,		100		Mil				0.5			V
VOL	Output LOW voltage			Com				0.45			٧
				12mA						0.4	V
				24mA						0.5(c)	٧
			/il				120		45	mA	
ICC	Supply Current	V _{CC} = Max	C	om				105		37	mA

See BIPOLAR & MOS MEMORY DATA MANUAL for 54S/74S89 AC Characteristics NOTES

For family dc characteristics, see inside front cover for 54/74 and 54H/74H, and see inside back cover for 54S/74S and 54LS/74LS specifications

c. This parameter for Commercial Range only.